## **Supporting information**

## Dopant-free multilayer back contact silicon solar cells employing $V_2O_x/metal/V_2O_x \ as \ an \ emitter$

Weiliang Wu<sup>ab</sup>, Wenjie Lin<sup>b</sup>, Jie Bao<sup>a</sup>, Zongtao Liu<sup>bc</sup>, Binhui Liu<sup>b</sup>, Kaifu Qiu<sup>b</sup>, Yifeng Chen<sup>\*d</sup> & Hui

Shen\*bcd

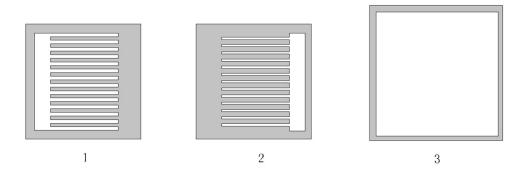
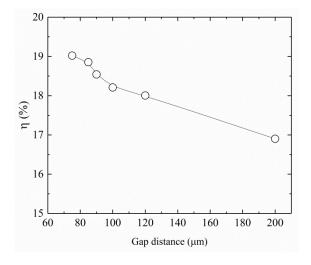


Figure S1 The three metal patterning masks for alignment



<sup>&</sup>lt;sup>a</sup> School of Electronics and Information Technology, Sun Yat-Sen University, Higher Education Mega Center, Guangzhou, Guangdong Province, PR China

<sup>&</sup>lt;sup>b</sup> Institute for Solar Energy Systems, School of Physics, 5th Floor, C Block, Building of Engeneering, 132 Wai Huan Dong Road, Sun Yat-Sen University, Guangzhou, Guangdong Province, PR China

<sup>&</sup>lt;sup>c</sup> Shunde-SYSU Institute for Solar Energy, Beijiao town, Shunde, Guangdong Province, 528300, PR China

<sup>&</sup>lt;sup>d</sup> State Key Laboratory of PV Science and Technology, Trina Solar, Changzhou, Jiangsu, China

Figure S2 Efficiency as a function of the gap distance

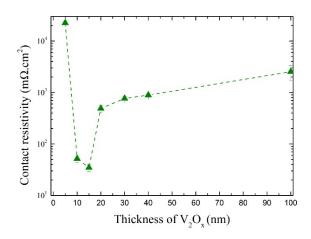


Figure S3: The dependence of contact resistance  $\rho_c$  values for  $V_2O_x$ /n-Si contacts on  $V_2O_x$  thickness, as respectively measured and fitted using the transfer length method (TLM).

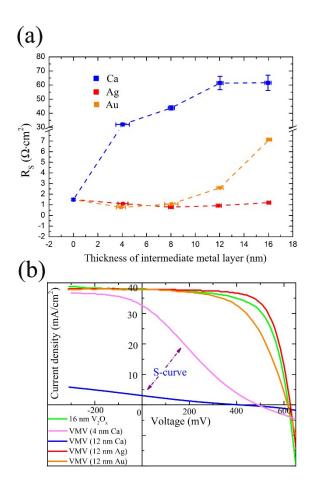


Figure S4: (a) The dependence of series resistance  $R_S$  values for VMV/n-Si solar cell. (b) The

J-V characteristic curves of different emitters.

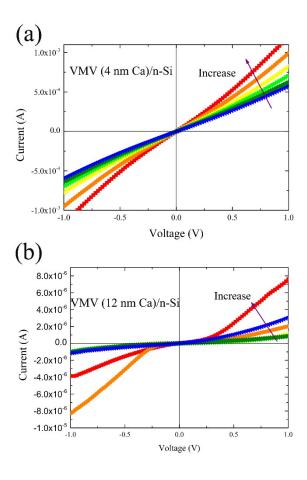


Figure S5: (a) and (b) show a serial of I–V measurements of sample with VMV (Ca)/n-Si contacts using the transfer length method (TLM).

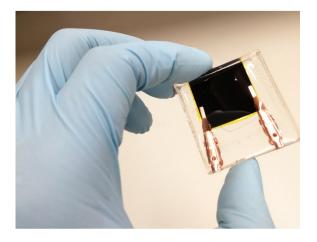


Figure S6: The image of a finished MLBC solar cells with VMV (4 nm Au) as emitter.